On the Use of Deep Learning for Image/Video Coding and Visual Quality Assessment

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Message from the Guest Editors

Dear Colleagues,

With the development of imaging and display technologies, ultra-high-definition, high dynamic range, high frame rate and immersive 360-degree contents have emerged in our lives. In order to address the challenges caused by a large amount of data, it is desirable to design efficient image/video compression algorithms. Moreover, it is important to have an effective tool to reliably assess, control and ensure high quality.

Today, artificial intelligence (AI) is widely used in academia and industry. Deep learning, and especially convolutional neural networks (CNN), is regarded as one of the important AI technologies that has been successfully applied in areas such as image processing, computer vision, and pattern recognition. Currently, the traditional video compression and visual quality assessment methods face a lot of challenges. Deep learning provides a new way to solve these problems.

This Special Issue is intended for researchers and practitioners from academia as well as industry who are interested in issues that arise from using deep learning for video data compression and visual quality assessment.

Special Issue

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Message from the Editor-in-Chief

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